


<b>Search Notes</b>  	<b>Application/Control No.</b>  10526400	<b>Applicant(s)/Patent Under Reexamination</b>  POYKKO ET AL.
	<b>Examiner</b>  NAM HUYNH	<b>Art Unit</b>  2617

SEARCHED			
Class	Subclass	Date	Examiner
See	Previous	12/6/2006	NTH

SEARCH NOTES		
Search Notes	Date	Examiner
See EAST search notes.	7/18/2008	NTH
See EAST search notes.	4/7/2009	NTH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner